Random bad cell map for wafer 162 s/n: Y21316-12-17

Date: 07/01/99

		289		0	6			
		0	0	0	0	0		
	0	0	0	0			0	
		0	0	1	0	0	260	
1	0	0	2	7	2	0	103	0
	0	0	18	43	13		0	2
	0	0		67	48	0	0	37
0	0	2	85	60	115	0	0	0
0			45	4	157	4	0	
0		3	63	9	109	2		
0	0	1	28	34		1		0
16	0	0	20	34		0		0
0	506	0	2			0	0	0
0	0	0			7	0	3	0
	3	0	1	0	0	0		
	0	15	0	0	4	0	291	
		0	0	0	0	0		
			0	0	0	0		

#	Number of bad cells in random locations
	No info